

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		PTVS7V5S1UR-Q						
		Part Description						
		Nexperia DHAM Protection						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113	24 5					
	PC	Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85%	24 hours 168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	438	24630	0		
# A1		MIL-STD-750-1	,	430	24030	0		
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	166	10040	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	131	7760	0		
# A3 <b>or</b>	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %						
# A3 <b>O</b> F	Ulibiased HAST	, , , , , , , , , , , , , , , , , , ,	96 hours	131	7760	0		
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
# A3 all	Autociave	11033dic = 203 ki d (23.7 p3id)						
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	131	7760	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta Tj$ =						
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.		
	<b>DO</b> 11	150000 4444						
	RSH	JESD22-A111		.=		_		
# C8	Resistance to Solder Heat	200 °C ± 5 °C	10 s	45	1350	0		
# C10	<b>SD</b> Solderability	J-STD-002		111	1110	0		
# CIU	Joiderability	J J1D 002		111	1110	0		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Protection	10040	0	0,42	2,36E+09

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